

**Search Notes**

Application/Control No.

10/538,715

Examiner

TAEYOON KIM

Applicant(s)/Patent under  
Reexamination

FARDEAU ET AL.

Art Unit

1651

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
updated search (sequence search: SCORE)	9/4/2008	TK